New Jersey Semi-Conductor Products, Inc.

20 STERN AVE. SPRINGFIELD, NEW JERSEY 07081 U.S.A.

# TELEPHONE: (973) 376-2922 IRF350/351/352/353 IRF350R/351R/352R/353R

# N-Channel Power MOSFETs Avalanche Energy Rated\*

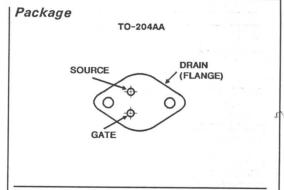
#### Features

- 13A and 15.0A, 350V 400V
- r<sub>DS</sub>(on) = 0.3Ω and 0.4Ω
- Single Pulse Avalanche Energy Rated\*
- SOA is Power-Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- · High Input Impedance

#### Description

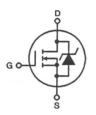
The IRF350, IRF351, IRF352, and IRF353 are n-channel enhancement-mode silicon-gate power field-effect transistors. IRF350R, IRF351R, IRF352R and IRF353R types are advanced power MOSFETs designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching converters, motor drivers, relay drivers, and drivers for high-power bipolar switching transistors requiring high speed and low gate-drive power. These types can be operated directly from integrated circuits.

The IRF types are supplied in the JEDEC TO-204AA steel package.



#### Terminal Diagram

N-CHANNEL ENHANCEMENT MODE



Absolute Maximum Ratings (T<sub>C</sub> = +25°C), Unless Otherwise Specified

	IRF350 IRF350R	IRF351 IRF351R	IRF352 IRF352R	IRF353 IRF353R	UNITS
Drain-Source Voltage (1) VDS	400	350	400	350	V
Drain-Gate Voltage ( $R_{GS} = 20k\Omega$ ) (1) VDGR	400	350	400	350	v
Continuous Drain Current					
$T_{C} = +25^{\circ}C$ $I_{D}$	15	15	13	13	A
$T_{C} = +100^{\circ}C$ $I_{D}$	9.0	9.0	8.0	8.0	A
Pulsed Drain Current (3) IDM	60	60	52	52	A
Gate-Source Voltage VGS	±20	±20	±20	±20	V
Maximum Power Dissipation					
$T_{C} = +25^{\circ}C$ PD	150	150	150	150	w
Linear Derating Factor	1.2	1.2	1.2	1.2	W/ºC
Inductive Current, Clamped ILM (See Figure 14, L = 100µH)	60	60	52	52	Α
Single Pulse Avalanche Energy Rating (4) EAS*	700	700	700	700	mj
Operating and Storage Junction	-55 to +150	-55 to +150	-55 to +150	-55 to +150	oC
Maximum Lead Temperature for Soldering	300	300	300	300	oC
NOTES:					
1. $T_J = +25^{\circ}C$ to $+150^{\circ}C$ .	4. Vnn =	= 40V, starting T	= +25°C. L =	5.66mH, R <sub>GS</sub> = 8	50Ω IDEAK =
<ol> <li>Pulse Test: Pulse width ≤ 300µs, Duty Cycle ≤ 2%.</li> </ol>	15A. S	ee Figure 15.			PEAK
<ol> <li>Repetitive rating: Pulse width limited by maximum junction temperature See Transient Thermal Impedance Curve (Figure 5).</li> </ol>	е.				
*R Suffix Types Only					

CAUTION: These devices are sensitive to electrostatic scharge. Proper I.C. handling procedures should be followed.

NJ Semi-Conductors reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by NJ Semi-Conductors is believed to be both accurate and reliable at the time of going to press. However, NJ Semi-Conductors assumes no responsibility for any errors or omissions discovered in its use. NJ Semi-Conductors encourages customers to verify that datasheets are current before placing orders.



Quality Sami Canductors

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CHARACTERISTIC	SYMBOL		LIMITS			
		TEST CONDITIONS	MIN	TYP	MAX	UNITS
Drain-Source Breakdown Voltage IRF350/352, IRF350R/352R	BVDSS	$V_{GS} = 0V, I_{D} = -250 \mu A$	400	-	-	v
IRF351/353, IRF351R/353R	1		350	-	-	V
Gate Threshold Voltage	VGS(TH)	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	2.0	-	4.0	V
Gate-Source Leakage Forward	IGSS	$V_{GS} = 20V$	· · · -	-	100	nA
Gate-Source Leakage Reverse	IGSS	V <sub>GS</sub> = -20V	-		-100	nA
ro Gate Voltage Drain Current IDSS VDS = Max Rating, VGS = 0V		-	-	250	μA	
Carry and		$V_{DS} = Max Rating x 0.8, V_{GS} = 0V,$ T <sub>J</sub> = +125°C	-	-	1000	μА
On-State Drain Current (Note 2) IRF350/351, IRF350R/351R	ID(ON)	V <sub>DS</sub> > I <sub>D(ON)</sub> × r <sub>DS(ON)</sub> Max, V <sub>GS</sub> = 10V	15	-	-	A
IRF352/353, IRF352R/353R			13	-	-	A
Static Drain-Source On-State Resistance (Note 2) IRF350/351, IRF350R/351R	rDS(ON)	$V_{GS} = 10V, I_{D} = 8.0A$	-	0.25	0.3	Ω
IRF352/353, IRF352R/353R	1		-	0.3	0.4	Ω
Forward Transconductance (Note 2)	9ts	$V_{DS} > I_{D(ON)} \times r_{DS(ON)Max}$ , $I_{D} = 8.0A$	8.0	10	-	S(75)
Input Capacitance	CISS	$V_{GS} = 0V, V_{DS} = 25V, f = 1.0MHz$	-	2000	-	DF
Output Capacitance	Coss	See Figure 10	-	400	-	pF
Reverse Transfer Capacitance	CRSS		-	100	-	DF
Turn-On Delay Time	td(ON)	$V_{DD} \simeq 180V, I_D = 8.0A, Z_0 = 4.7\Omega$	-	-	35	ns
Rise Time	tr	See Figure 16. (MOSFET switching times	-	-	65	ns
Turn-Off Delay Time	td(OFF)	are essentially independent of operating temperature)	-	-	150	ns
Fall Time	tf	(importation)	-	-	75	ns
Total Gate Charge (Gate-Source + Gate-Drain)	Qg	$V_{GS} = 10V$ , $I_D = 18A$ , $V_{DS} = 0.8V$ Max Rating. See Figure 17 for test circuit.	-	79	120	nC
Gate-Source Charge	Qgs	(Gate charge is essentially independent of operating temperature.)	-	38		nC
Gate-Drain ("Miller") Charge	Qgd	operating temperature.)	-	41	-	nC
Internal Drain Inductance	LD	Measured between the contact screw on header that is closer to source and gate pins and center of center of die. Modified MOSFET symbol showing the internal device inductances. D	-	5.0	-	nH
Internal Source Inductance	LS	Measured from the source lead, 6mm (0.25'') from header and source bonding pad.	-	12.5	-	nH
Junction-to-Case	R <sub>0JC</sub>		-	-	0.83	°C/W
Case-to-Sink	Recs	Mounting surface flat, smooth and greased	-	0.1	-	°C/W
Junction-to-Ambient	R <sub>0JA</sub>	Free air operation	-	-	30	°C/W

### IRF350, IRF351, IRF352, IRF353 IRF350R, IRF351R, IRF352R, IRF353R

#### Source Drain Diode Ratings and Characteristics

Continuous Source Current (Body Diode)	Is	Modified MOSFET symbol showing the	-	-	15	A
Pulse Source Current (Body Diode) (Note 3)	ISM	P-N junc. rectifier.	-	-	60	A
Diode Forward Voltage (Note 2)	VSD	$T_J = +25^{\circ}C, I_S = 15A, V_{GS} = 0V$	-	-	1.6	v
Reverse Recovery Time	trr	$T_J = +150^{\circ}C$ , $I_F = 15A$ , $dI_F/dt = 100A/\mu s$	-	1000	-	ns
Reverse Recovered Charge	QRR	$T_J = +150^{\circ}C$ , $I_F = 15A$ , $dI_F/dt = 100A/\mu s$	-	6.6	-	μC
Forward Turn-on Time	tON	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $L_S + L_D$ .	-		-	-

Pulse Test: Pulse width ≤ 300µs, Duty Cycle ≤ 2%

junction temperature. See Transient Thermal Impedance Curve (Figure 5)

 $R_{GS} = 50\Omega$ , IPEAK = 15A (See Figure 15)

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